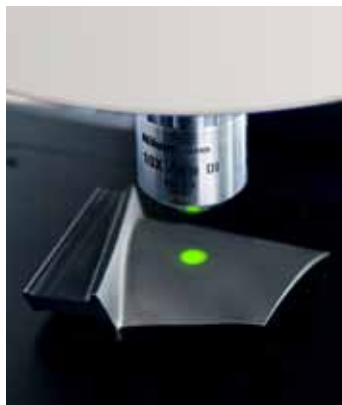
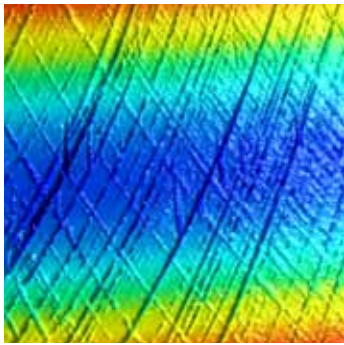


CCI MP-L

World-leading tools for 3D metrology



The CCI MP-L

Opening up the world of 3D profiling



Optical interferometry without compromise

- 500 micron vertical range with closed loop piezoless Z axis scanner
- 3.0 nm z resolution – independent of FOV
- 1024 x 1024 pixel array provides high resolution and a large FOV
- Better linearity than piezo scanners – better form measurement

Industry leading data quality

- <0.06% step height repeatability
- Claritas 20 light conditioning increases angle sensitivity improving data quality
- Calibration utilising traceable standards ensures acceptance of results
- Automatic set-up features eliminate operator variability

Robust design ensures low cost of ownership

- Piezoless Z axis scanner eliminates expensive repair bills
- Automatic surface detection prevents crash damage to lens
- Built in self-diagnostic tools for quick and easy troubleshooting
- Ease of use reduces the possibility of operator error

64-bit control and analysis software

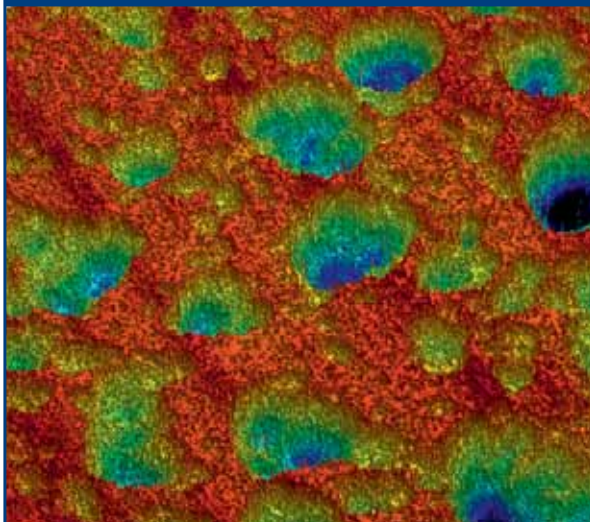
- Multi-language support to ease communication
- Optional 64-bit AutoStitch offers fast stitching over large areas
- Analysis tools including 4D analysis of 3D surfaces as they evolve over time
- Automatic report generation based on batches of measurement data



Unrivalled application possibilities

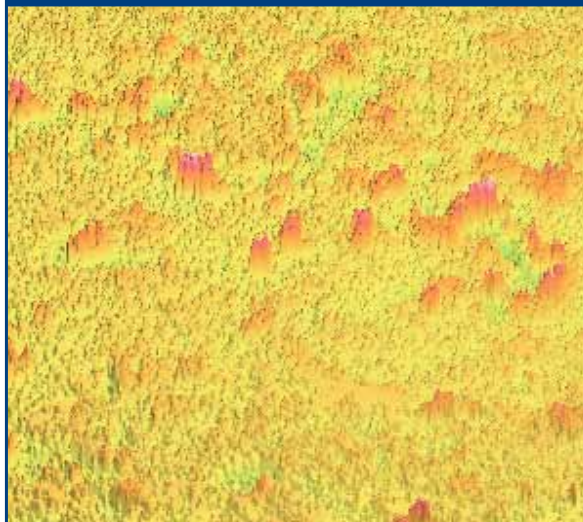
CCI **MP-L** provides a wide range of measurement options

Corroded surfaces



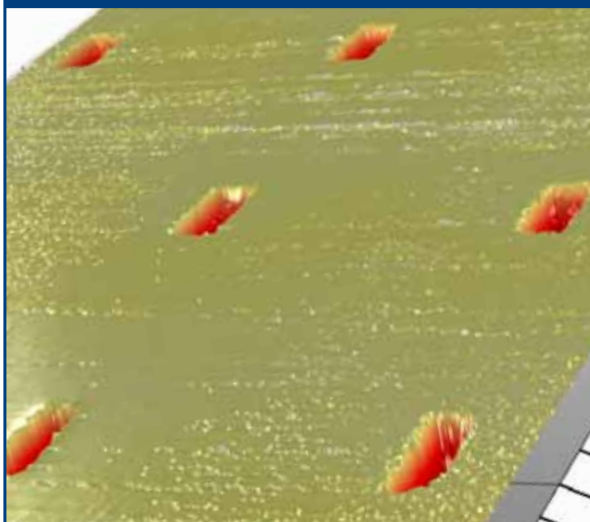
Complex surfaces such as corroded samples need a modern interferometer to understand the detailed surface. The range and resolution of the CCI MP-L are critical for this type of measurement.

Rough machined surfaces



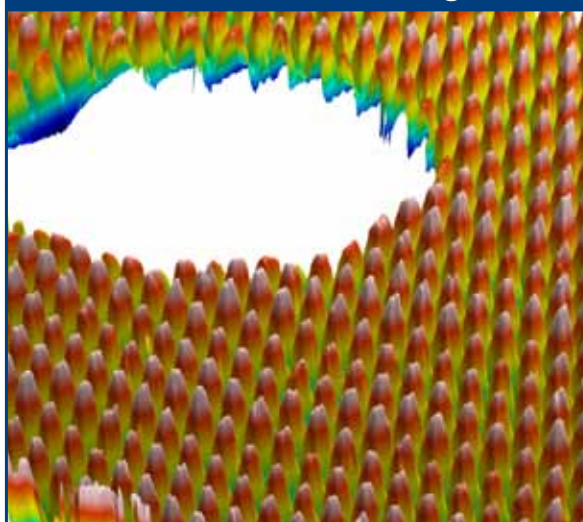
Because rough surfaces scatter light they are often difficult to measure. The unique CCI algorithm and high sensitivity camera gives less missing data points than any of our leading competitors.

Structured surface – dimples



Modern engineering surfaces have dimples in the surface to retain the lubrication fluids. CCI is ideal for measuring the spacing and dimensions of the pits

Structured surface – sealing surface

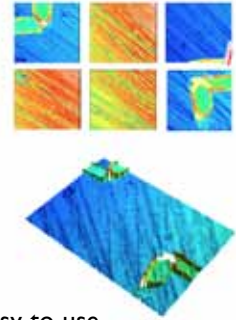


The CCI MP-L is ideal for studying structured surfaces used for sealing. The detail obtained can be used for controlling surface manufacture

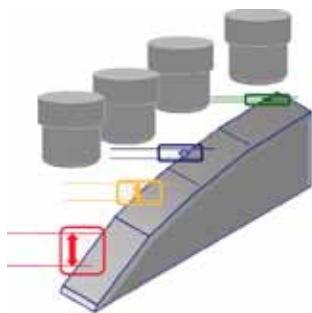
CCI MP-L is an industry-changing blend of science, experience and imagination with high quality 3D measurement

Range, resolution, accuracy, reliability – our formula for your success

Confidence in your 3D areal measurement result is assured with the revolutionary CCI non-contact optical profilers. The high resolution camera and unique algorithm, deliver a powerful analysis tool for many surface types. Powerful software analysis tools help researchers and developers keep pace with the latest developments whilst also enabling high speed and high quality process control. Optional software modules such as AutoStitch offer an extension to the CCI MP-L functionality



Optional AutoStitch – powerful yet easy to use



AutoFringeFind and AutoRange automatically optimizes scan range making measurement quicker and easier

Ease-of-use – reduces the cost of operator training

Automatic surface detection

AutoFringeFind increases inspection throughput by eliminating manual set-up. Unlike auto focus routines which require a flat and smooth surface, this innovative coupling of software and optical expertise can detect all types of surfaces quickly and automatically.

Automatic range setting

Significant reductions in measurement time are achieved with our AutoRange feature which automatically sets the optimum scan range based on the sample surface.

Universal measurement of different surfaces

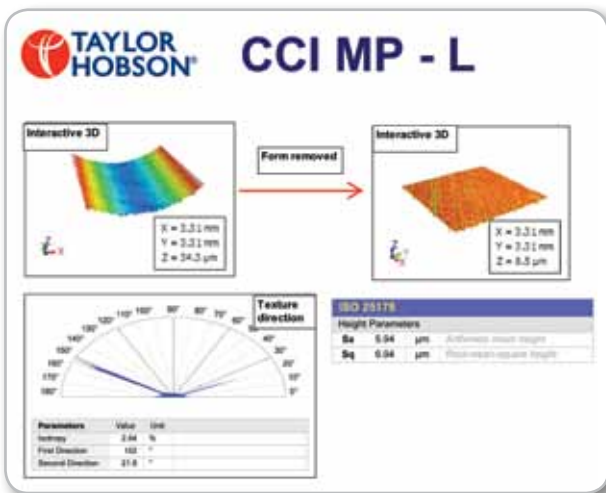
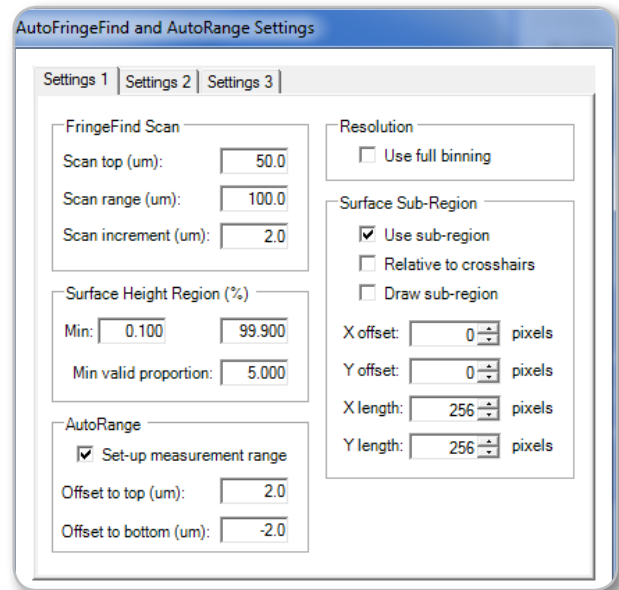
Streamline your inspection program by eliminating multiple inspection routines and incompatible measurement reports. Our patented Coherence Correlation algorithm provides detailed data regardless of scanning range so that all surfaces at any stage in production can be measured on the same instrument using the same measuring technique.

Powerful software options

Flexible control software

Now with 64-bit processing, the CCI control software features more flexibility, faster operating speed and improved overall performance. Customisable template functionality make TalyMap software the ideal analysis software platform.

Multi-language support is now available to keep pace with the global economy and international manufacturing partnerships.



TalyMap analysis software

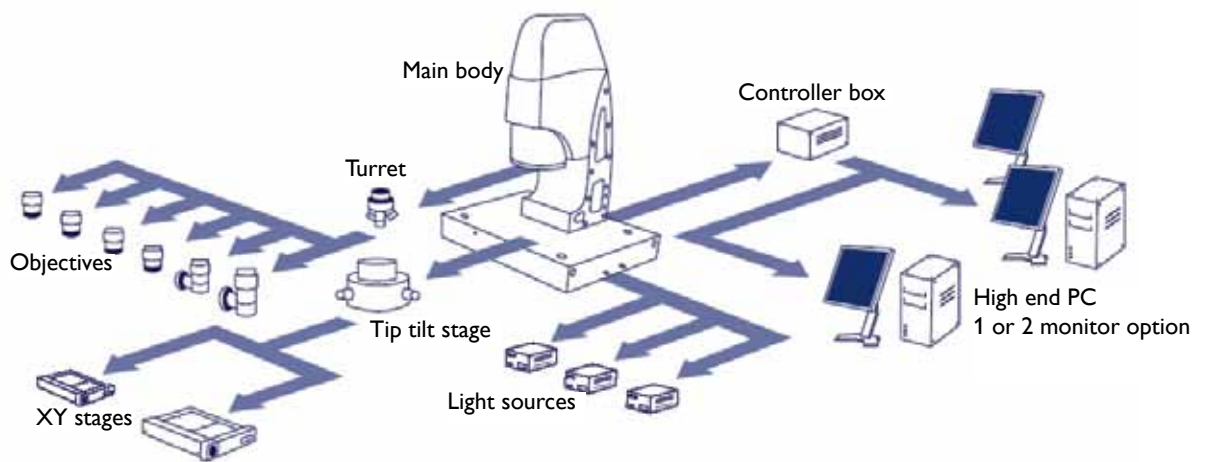
Research facilities, factories and universities worldwide have made TalyMap their preferred surface analysis software. It is used for product development, process improvement, predictive behaviour analysis and routine inspection in many sectors.

TalyMap is continuously evolved by a multi-disciplinary team of specialists in metrology, software engineering and automation in order to meet present and future surface metrology needs.

Key features

- **Full metrological traceability** with a new analysis workflow that makes it easy to trace every step in an analysis document. New steps can be added and existing steps can be fine-tuned or deleted at any time.
- **Statistics for quality control** makes it possible to track and generate statistics on parameters across multiple measurement data sets.
- **Multi-language support** gives options to change the software to work in one of six European languages, Japanese, Chinese, Korean or Brazilian Portuguese.
- **Quick results** achieved from the Minidoc function, where any sequence of analysis steps can be defined and saved into a Minidoc library, significantly speeding up the preparation of new reports.
- **Customisation** allows you to add company logos, measurement identity cards, screen notes and illustrations including bitmaps, text blocks, arrows.
- **Advanced Modules** enhance the functionality of TalyMap by providing additional analysis or presentation capabilities.

System Configurations



Specifications are subject to change without notice

	CCI MP-L	CCI MP
No. of pixels	1M pixel	1M pixel
Roughness	✓	✓
Step height	✓	✓
TalyMap Lite	✓	✓
TalyMap Upgrade	●	●
500 micron scan range	✓	✗
2.2 mm scan length	●	✓
Stitching	●	✓
Multi-site	●	✓
Standard lens	20x	20x
Other lenses	●	●
Joystick	●	●
Manual 25 mm x 25 mm stage	✓	✗
Automatic 112 x 78 mm stage	●	✓
Automatic 156 x 156 mm stage	●	●
Internal AV	✓	✓

✓ = Included ● = Optional ✗ = Not available

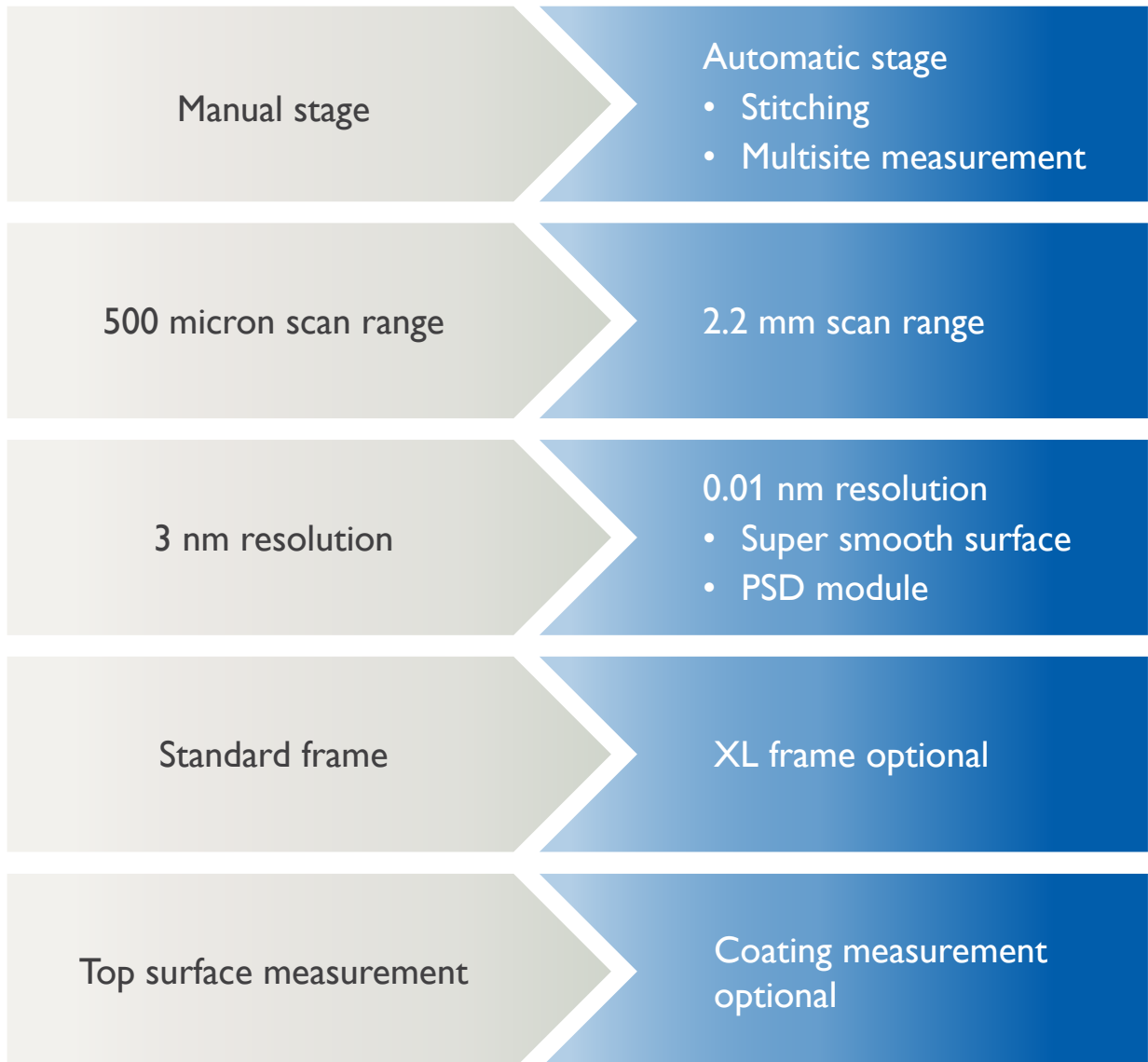
Upgrade path



CCI MP-L



CCI MP



Serving a global market

Taylor Hobson is world renowned as a manufacturer of precision measuring instruments used for inspection in research and production facilities. Our equipment performs at nanometric levels of resolution and accuracy.

To complement our precision manufacturing capability we also offer a host of metrology support services to provide our customers with complete solutions to their measuring needs and total confidence in their results.

Contracted services from Taylor Hobson

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Tel: **+44 (0)116 246 2034**

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special purpose, dedicated metrology systems for demanding applications
- **Precision manufacturing**
contract machining services for high precision applications and industries

Service department

Email: taylor-hobson.service@ametek.com

Tel: **+44 (0)116 246 2900**

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protect your metrology investment with an Amecare support agreement

Centre of Excellence department

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measurement of your production parts by skilled technicians using industry leading instruments in accord with ISO standards
- **Metrology training**
practical, hands-on training courses for roundness and surface finish conducted by experienced metrologists
- **Operator training**
on-site instruction will lead to greater proficiency and higher productivity
- **UKAS calibration and testing**
certification for artifacts or instruments in our laboratory or at customer's site



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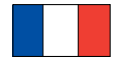
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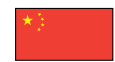
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